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GB/T 14849.4-2008

Methods for chemical analysis of silicon metal - Part 4: Determination of elements content Inductively coupled plasma atomic emission spectrometric method

工业硅化学分析方法 第4部分：电感耦合等离子体原子发射光谱法测定元素含量

(English Translation)

Issued on: June 9, 2008 **Implemented on: December 1, 2008**

Issued by: General Administration of Quality Supervision, Inspection and Quarantine of the People's Republic of China;
Standardization Administration of China

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Document data

1 Document data

Sector: National standard (Recommended).

Issuing body: General Administration of Quality Supervision, Inspection and Quarantine of the People's Republic of China; Standardization Administration of China.

Date of issue: 2008-06-09.

Date of implementation: 2008-12-01.

Status: obsolete, replaced by GB/T 14849.4-2014.

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https://chinastandards.org/standards/gb-t-14849-4-2008